

**Notice of References Cited**

 Application/Control No.  
 09/754,335

 Applicant(s)/Patent Under  
 Reexamination  
 FARDELLA ET AL.

Examiner

Hai V. Nguyen

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 2142

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-6,360,221	03-2002	Gough et al.	707/10
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	K	US-			
	L	US-			
	M	US-			

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	N					
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**NON-PATENT DOCUMENTS**

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